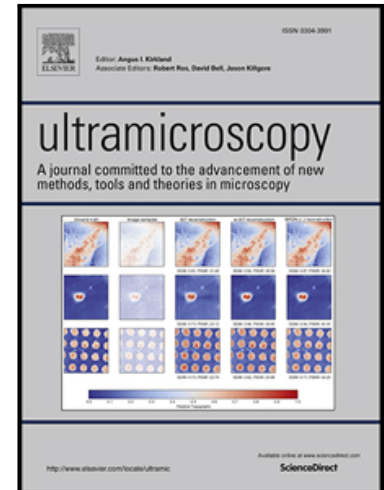


Accepted Manuscript

Atomic resolution force imaging through the static deflection of the cantilever in simultaneous Scanning Tunneling/Atomic Force Microscopy

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PII: S0304-3991(18)30254-7
DOI: <https://doi.org/10.1016/j.ultramic.2018.09.018>
Reference: ULTRAM 12662



To appear in: *Ultramicroscopy*

Received date: 22 July 2018
Revised date: 17 September 2018
Accepted date: 20 September 2018

Please cite this article as: H. Özgür Özer , Atomic resolution force imaging through the static deflection of the cantilever in simultaneous Scanning Tunneling/Atomic Force Microscopy, *Ultramicroscopy* (2018), doi: <https://doi.org/10.1016/j.ultramic.2018.09.018>

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Highlights

- True atomic resolution obtained through the static deflection of the cantilever
- Force perfectly agrees with force gradient obtained from oscillations
- Deflection reveals force in small amplitude simultaneous STM/AFM operation

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